- Meet or Exceed the Requirements of TIA/EIA-422-B, TIA/EIA-485-A $\dagger$ and ITU Recommendations V. 11 and X. 27
- Operate at Data Rates up to 35 Mbaud
- Four Skew Limits Available:

SN65ALS176... 15 ns
SN75ALS176 ... 10 ns
SN75ALS176A... 7.5 ns
SN75ALS176B . . . 5 ns

- Designed for Multipoint Transmission on Long Bus Lines in Noisy Environments
- Low Supply-Current Requirements ... 30 mA Max
- Wide Positive and Negative Input/Output Bus-Voltage Ranges
- Thermal Shutdown Protection
- Driver Positive and Negative Current Limiting
- Receiver Input Hysteresis
- Glitch-Free Power-Up and Power-Down Protection
- Receiver Open-Circuit Fail-Safe Design


## description

D OR P PACKAGE
(TOP VIEW)


The SN65ALS176 and SN75ALS176 series differential bus transceivers are designed for bidirectional data communication on multipoint bus transmission lines. They are designed for balanced transmission lines and meet TIA/EIA-422-B, TIA/EIA-485-A, and ITU Recommendations V. 11 and X. 27.
The SN65ALS176 and SN75ALS176 series combine a 3-state, differential line driver and a differential input line receiver, both of which operate from a single 5-V power supply. The driver and receiver have active-high and active-low enables, respectively, that can be connected together externally to function as a direction control. The driver differential outputs and the receiver differential inputs are connected internally to form a differential input/output (I/O) bus port that is designed to offer minimum loading to the bus when the driver is disabled or $\mathrm{V}_{\mathrm{CC}}=0$. This port features wide positive and negative common-mode voltage ranges, making the device suitable for party-line applications.
The SN65ALS176 is characterized for operation from $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$. The SN75ALS176 series is characterized for operation from $0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}$.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

[^0]AVAILABLE OPTIONS

| $\mathbf{T}_{\mathbf{A}}$ | $\mathbf{t}_{\mathbf{s k}(\text { lim })}{ }^{\dagger}$ | PACKAGED DEVICES |  |
| :---: | :---: | :---: | :---: |
|  |  | $\begin{array}{c}\text { SMALL OUTLINE } \\ \text { (D) } \ddagger\end{array}$ | $\begin{array}{c}\text { PLASTIC DIP } \\ \text { (P) }\end{array}$ |
| $0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}$ | 10 | $\begin{array}{c}\text { SN75ALS176D }\end{array}$ | $\begin{array}{c}\text { SN75ALS176P } \\ \text { SN75ALS176AD } \\ \end{array}$ |
| $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$ | 15 | $\begin{array}{c}\text { SN75ALS176AP } \\ \text { SN75ALS176BD }\end{array}$ |  |
| SN75ALS176BP |  |  |  |$]$

$\dagger$ This is the maximum range that the driver or receiver delay times vary over temperature, $\mathrm{V}_{\mathrm{CC}}$, and process (device to device).
$\ddagger$ The $D$ package is available taped and reeled. Add the suffix $R$ to the device type (e.g., SN75ALS176DR).

Function Tables

| INPUT | ENABLE | OUTPUTS |  |
| :---: | :---: | :---: | :---: |
| D | DE | A | B |
| $H$ | $H$ | $H$ | L |
| L | H | L | H |
| X | L | Z | Z |

$H=$ high level, $L=$ low level, $X=$ irrelevant, Z = high impedance
RECEIVER

| DIFFERENTIAL <br> INPUTS <br> A-B | ENABLE <br> $\overline{R E}$ | OUTPUT <br> $\mathbf{R}$ |
| :---: | :---: | :---: |
| $\mathrm{V}_{\text {ID }} \geq 0.2 \mathrm{~V}$ | L | H |
| $-0.2 \mathrm{~V}<\mathrm{V}_{\text {ID }}<0.2 \mathrm{~V}$ | L | $?$ |
| $\mathrm{~V}_{\mathrm{ID}} \leq-0.2 \mathrm{~V}$ | L | L |
| X | H | Z |
| Inputs open | L | H |

$H=$ high level, $L=$ low level, $X=$ irrelevant, $\mathrm{Z}=$ high impedance
logic symbol§

§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
logic diagram (positive logic)


## schematics of inputs and outputs

EQUIVALENT OF EACH INPUT

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted) $\dagger$

Supply voltage, $\mathrm{V}_{\mathrm{CC}}$ (see Note 1) ..... 7 V
Voltage range at any bus terminal ..... -7 V to 12 V
Enable input voltage, $\mathrm{V}_{\mathrm{I}}$ ..... 5.5 V
Package thermal impedance, $\theta_{\text {JA }}$ (see Note 2): D package ..... $97^{\circ} \mathrm{C} / \mathrm{W}$
P package ..... $8^{\circ} \mathrm{C} / \mathrm{W}$
Lead temperature $1,6 \mathrm{~mm}$ ( $1 / 16 \mathrm{inch}$ ) from case for 10 seconds ..... $260^{\circ} \mathrm{C}$
Storage temperature range, $T_{\text {stg }}$ ..... $-65^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$
$\dagger$ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
NOTES: 1. All voltage values, except differential I/O bus voltage, are with respect to network ground terminal.
2. The package thermal impedance is calculated in accordance with JESD 51.
recommended operating conditions (unless otherwise noted)

|  |  | MIN | NOM | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Supply voltage, $\mathrm{V}_{\mathrm{CC}}$ |  | 4.75 | 5 | 5.25 | V |
| Input voltage at any bus terminal (separately or common mode), $\mathrm{V}_{1}$ or $\mathrm{V}_{\text {IC }}$ |  |  |  | 12 | V |
| High-level input voltage, $\mathrm{V}_{\text {IH }}$ | D, DE, and $\overline{\mathrm{RE}}$ | 2 |  |  | V |
| Low-level input voltage, $\mathrm{V}_{\text {IL }}$ | D, DE, and $\overline{\mathrm{RE}}$ |  |  | 0.8 | V |
| Differential input voltage, $\mathrm{V}_{\text {ID }}$ (see Note 3) |  |  |  | $\pm 12$ | V |
| High-level output current, IOH | Driver |  |  | -60 | mA |
|  | Receiver |  |  | -400 | $\mu \mathrm{A}$ |
| Low-level output current, IOL | Driver |  |  | 60 | mA |
|  | Receiver |  |  | 8 |  |
| Operating free-air temperature, $\mathrm{T}_{\mathrm{A}}$ | SN65ALS176 | -40 |  | 85 | ${ }^{\circ} \mathrm{C}$ |
|  | SN75ALS176 series | 0 |  | 70 |  |

NOTE 3: Differential input/output bus voltage is measured at the noninverting terminal $A$ with respect to the inverting terminal $B$.

## DRIVER SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted)

|  | PARAMETER | TEST CONDITIONS $\dagger$ |  | MIN | TYP $\ddagger$ | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {IK }}$ | Input clamp voltage | $\mathrm{I}_{\mathrm{I}}=-18 \mathrm{~mA}$ |  |  |  | -1.5 | V |
| $\mathrm{V}_{\mathrm{O}}$ | Output voltage | $\mathrm{I}=0$ |  | 0 |  | 6 | V |
| \|VOD1 ${ }^{\text {l }}$ | Differential output voltage | $\mathrm{I}=0$ |  | 1.5 |  | 6 | V |
| \| $\mathrm{V}_{\text {OD2 }} \mid$ | Differential output voltage | $R_{L}=100 \Omega$, | See Figure 1 | $\begin{aligned} & 1 / 2 \mathrm{~V}_{\mathrm{OD} 1} \\ & \text { or } 2 \S \end{aligned}$ |  |  | V |
|  |  | $\mathrm{R}_{\mathrm{L}}=54 \Omega$, | See Figure 1 | 1.5 | 2.5 | 5 | V |
| VOD3 | Differential output voltage | $\mathrm{V}_{\text {test }}=-7 \mathrm{~V}$ to 12 V , | See Figure 2 | 1.5 |  | 5 | V |
| $\Delta\left\|\mathrm{V}_{\text {Od }}\right\|$ | Change in magnitude of differential output voltage ${ }^{I}$ | $\mathrm{R}_{\mathrm{L}}=54 \Omega$ or $100 \Omega$, | See Figure 1 |  |  | $\pm 0.2$ | V |
| VOC | Common-mode output voltage | $\mathrm{R}_{\mathrm{L}}=54 \Omega$ or $100 \Omega$, | See Figure 1 |  |  | 3 | V |
| $\Delta \mid \mathrm{VOCl}$ | Change in magnitude of common-mode output voltagel | $\mathrm{RL}=54 \Omega$ or $100 \Omega$, | See Figure 1 |  |  | $\pm 0.2$ | V |
| Io | Output current | Outputs disabled (see Note 4) | $\mathrm{V}_{\mathrm{O}}=12 \mathrm{~V}$ |  |  | 1 | mA |
|  |  |  | $\mathrm{V}_{\mathrm{O}}=-7 \mathrm{~V}$ |  |  | -0.8 |  |
| $\mathrm{IIH}^{\text {H }}$ | High-level input current | $\mathrm{V}_{1}=2.4 \mathrm{~V}$ |  |  |  | 20 | $\mu \mathrm{A}$ |
| IIL | Low-level input current | $\mathrm{V}_{1}=0.4 \mathrm{~V}$ |  |  |  | -400 | $\mu \mathrm{A}$ |
| Ios | Short-circuit output current\# | $\mathrm{V}_{\mathrm{O}}=-4 \mathrm{~V}$ | SN65ALS176 |  |  | -250 | mA |
|  |  | $\mathrm{V}_{\mathrm{O}}=-6 \mathrm{~V}$ | SN75ALS176 |  |  | -250 |  |
|  |  | $\mathrm{V}_{\mathrm{O}}=0$ |  |  |  | -150 |  |
|  |  | $\mathrm{V}_{\mathrm{O}}=\mathrm{V}_{\mathrm{CC}}$ |  |  |  | 250 |  |
|  |  | $\mathrm{V}_{\mathrm{O}}=8 \mathrm{~V}$ |  |  |  | 250 |  |
| ICC | Supply current | No load | Outputs enabled |  | 23 | 30 | mA |
|  |  |  | Outputs disabled |  | 19 | 26 |  |

$\dagger$ The power-off measurement in TIA/EIA-422-B applies to disabled outputs only and is not applied to combined inputs and outputs.
$\ddagger$ All typical values are at $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ and $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.
§ The minimum $\mathrm{V}_{\mathrm{OD}}$ w with a $100-\Omega$ load is either $1 / 2 \mathrm{~V}_{\mathrm{OD} 1}$ or 2 V , whichever is greater.
$\mathrm{I}_{\Delta\left|\mathrm{V}_{\mathrm{OD}}\right| \text { and } \Delta\left|\mathrm{V}_{\mathrm{OC}}\right| \text { are the changes in magnitude of } \mathrm{V}_{\mathrm{OD}} \text { and } \mathrm{V}_{\mathrm{OC}} \text {, respectively, that occur when the input is changed from one logic state to the }}$ other.
\# Duration of the short circuit should not exceed one second for this test.
NOTE 4: This applies for power on and power off. Refer to TIA/EIA-485-A for exact conditions. The TIA/EIA-422-B limit does not apply for a combined driver and receiver terminal.
switching characteristics over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted)

SN65ALS176

|  | PARAMETER | TEST CONDITIONS |  |  | MIN | TYP $\dagger$ | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{t}_{\mathrm{d}(\mathrm{OD})}$ | Differential output delay time | $\mathrm{R}_{\mathrm{L}}=54 \Omega$, | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 3 |  |  | 15 | ns |
| $\mathrm{t}_{\text {sk }}(\mathrm{p})$ | Pulse skew $\ddagger$ | $\mathrm{R}_{\mathrm{L}}=54 \Omega$, | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 3 |  | 0 | 2 | ns |
| $\mathrm{t}_{\text {sk(lim) }}$ | Pulse skew§ | $\mathrm{R}_{\mathrm{L}}=54 \Omega$, | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 3 |  |  | 15 | ns |
| $\mathrm{t}_{\mathrm{t}}$ (OD) | Differential output transition time | $\mathrm{R}_{\mathrm{L}}=54 \Omega$, | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 3 |  | 8 |  | ns |
| tpZH | Output enable time to high level | $\mathrm{R}_{\mathrm{L}}=110 \Omega$, | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 4 |  |  | 80 | ns |
| tPZL | Output enable time to low level | $R_{L}=110 \Omega$, | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 5 |  |  | 30 | ns |
| tPHZ | Output disable time from high level | $\mathrm{R}_{\mathrm{L}}=110 \Omega$, | $\mathrm{CL}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 4 |  |  | 50 | ns |
| tplZ | Output disable time from low level | $\mathrm{R}_{\mathrm{L}}=110 \Omega$, | $\mathrm{CL}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 5 |  |  | 30 | ns |

$\dagger$ All typical values are at $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.
$\ddagger$ Pulse skew is defined as the |tpLH - tpHLl of each channel of the same device.
§ Skew limit is the maximum difference in propagation delay times between any two channels of any two devices.
SN75ALS176, SN75ALS176A, SN75ALS176B

| PARAMETER |  |  | TEST CONDITIONS |  |  | MIN | TYPt | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{t}_{\mathrm{d}}(\mathrm{OD})$ | Differential output delay time | 'ALS176 | $R_{L}=54 \Omega$, | $C_{L}=50 \mathrm{pF}$, | See Figure 3 | 3 | 8 | 13 | ns |
|  |  | 'ALS176A |  |  |  | 4 | 7 | 11.5 |  |
|  |  | 'ALS176B |  |  |  | 5 | 8 | 10 |  |
| tsk(p) | Pulse skew $\ddagger$ |  | $\mathrm{R}_{\mathrm{L}}=54 \Omega$, | $C_{L}=50 \mathrm{pF}$, | See Figure 3 |  | 0 | 2 | ns |
| ${ }_{\text {tsk }}$ (lim) | Pulse skew§ | 'ALS176 | $R_{L}=54 \Omega$, | $C_{L}=50 \mathrm{pF}$, | See Figure 3 |  |  | 10 | ns |
|  |  | 'ALS176A |  |  |  |  |  | 7.5 |  |
|  |  | 'ALS176B |  |  |  |  |  | 5 |  |
| $\mathrm{t}_{\mathrm{t}}(\mathrm{OD})$ | Differential output transition time |  | $\mathrm{R}_{\mathrm{L}}=54 \Omega$, | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 3 |  | 8 |  | ns |
| tPZH | Output enable time to high level |  | $\mathrm{R}_{\mathrm{L}}=110 \Omega$, | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 4 |  | 23 | 50 | ns |
| tPZL | Output enable time to low level |  | $\mathrm{R}_{\mathrm{L}}=110 \Omega$, | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 5 |  | 14 | 20 | ns |
| tPHZ | Output disable time from high level |  | $\mathrm{R}_{\mathrm{L}}=110 \Omega$, | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 4 |  | 20 | 35 | ns |
| tplZ | Output disable time from low level |  | $\mathrm{R}_{\mathrm{L}}=110 \Omega$, | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, | See Figure 5 |  | 8 | 17 | ns |

$\dagger$ All typical values are at $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.
$\ddagger$ Pulse skew is defined as the $\left|\mathrm{tpLH}-\mathrm{t}_{\mathrm{PHL}}\right|$ of each channel of the same device.
§ Skew limit is the maximum difference in propagation delay times between any two channels of any two devices.
SYMBOL EQUIVALENTS

| DATA-SHEET <br> PARAMETER | TIA/EIA-422-B | TIA/EIA-485-A |
| :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{O}}$ | $\mathrm{V}_{\mathrm{Oa}}, \mathrm{V}_{\mathrm{Ob}}$ | $\mathrm{V}_{\mathrm{Oa}}, \mathrm{V}_{\mathrm{ob}}$ |
| $\left\|\mathrm{V}_{\mathrm{OD} 1}\right\|$ | $\mathrm{V}_{\mathrm{O}}$ | $\mathrm{V}_{\mathrm{O}}$ |
| $\left\|\mathrm{V}_{\mathrm{OD} 2}\right\|$ | $\mathrm{V}_{\mathrm{t}}\left(\mathrm{R}_{\mathrm{L}}=100 \Omega\right)$ | $\mathrm{V}_{\mathrm{t}}\left(\mathrm{R}_{\mathrm{L}}=54 \Omega\right)$ |
| $\left\|\mathrm{V}_{\mathrm{OD} 3}\right\|$ | None | $\mathrm{V}_{\mathrm{t}}($ test termination <br> measurement 2) |
| $\Delta\left\|\mathrm{V}_{\mathrm{OD}}\right\|$ | $\left\|\left\|\mathrm{V}_{\mathrm{t}}\right\|-\left\|\overline{\mathrm{V}}_{\mathrm{t}}\right\|\right\|$ | $\\| \mathrm{V}_{\mathrm{t}}\left\|-\left\|\overline{\mathrm{V}}_{\mathrm{t}}\right\|\right\|$ |
| $\mathrm{V}_{\mathrm{OC}}$ | $\left\|\mathrm{V}_{\mathrm{OS}}\right\|$ | $\left\|\mathrm{V}_{\mathrm{OS}}\right\|$ |
| $\Delta\left\|\mathrm{V}_{\mathrm{OC}}\right\|$ | $\left\|\mathrm{V}_{\mathrm{OS}}-\overline{\mathrm{V}}_{\mathrm{OS}}\right\|$ | $\left\|\mathrm{V}_{\mathrm{OS}}-\overline{\mathrm{V}}_{\mathrm{OS}}\right\|$ |
| $\mathrm{I}_{\mathrm{OS}}$ | $\left\|\mathrm{I}_{\mathrm{sal}}\right\|,\left\|\mathrm{I}_{\mathrm{sb}}\right\|$ | None |
| $\mathrm{I}_{\mathrm{O}}$ | $\left\|\mathrm{I}_{\mathrm{xa}}\right\|,\left\|\mathrm{I}_{\mathrm{xb}}\right\|$ | $\mathrm{I}_{\mathrm{i}}, \mathrm{l}_{\mathrm{ib}}$ |

## RECEIVER SECTION

electrical characteristics over recommended ranges of common-mode input voltage, supply voltage, and operating free-air temperature range (unless otherwise noted)

| PARAMETER | TEST CONDITIONS |  | MIN | TYP† | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{1 \mathrm{~T}_{+}}$Positive-going input threshold voltage | $\mathrm{V}_{\mathrm{O}}=2.7 \mathrm{~V}$, | $\mathrm{I}=-0.4 \mathrm{~mA}$ |  |  | 0.2 | V |
| $\mathrm{V}_{\text {IT- }}$ Negative-going input threshold voltage | $\mathrm{V}_{\mathrm{O}}=0.5 \mathrm{~V}$, | $\mathrm{I} \mathrm{O}=8 \mathrm{~mA}$ | $-0.2 \ddagger$ |  |  | V |
| $\mathrm{V}_{\text {hys }}$ Hysteresis voltage ( $\mathrm{V}_{\text {IT }+}-\mathrm{V}_{\text {IT }}$ ) |  |  |  | 60 |  | mV |
| $\mathrm{V}_{\mathrm{IK}}$ Enable-input clamp voltage | $\mathrm{I}_{\mathrm{I}}=-18 \mathrm{~mA}$ |  |  |  | -1.5 | V |
| $\mathrm{V}_{\mathrm{OH}}$ High-level output voltage | $\mathrm{V}_{\mathrm{ID}}=200 \mathrm{mV} \text {, }$ <br> See Figure 6 | $\mathrm{IOH}=-400 \mu \mathrm{~A}$, | 2.7 |  |  | V |
| VOL Low-level output voltage | $\mathrm{V}_{\mathrm{ID}}=-200 \mathrm{mV} \text {, }$ <br> See Figure 6 | $\mathrm{l} \mathrm{OL}=8 \mathrm{~mA}$, |  |  | 0.45 | V |
| IOZ High-impedance-state output current | $\mathrm{V}_{\mathrm{O}}=0.4 \mathrm{~V}$ to 2.4 V |  |  |  | $\pm 20$ | $\mu \mathrm{A}$ |
| $V_{1}$ Line input current | $\text { Other input = } 0 \mathrm{~V}$ | $\mathrm{V}_{\mathrm{I}}=12 \mathrm{~V}$ |  |  | 1 | mA |
| V/ Line input current | (see Note 5) | $\mathrm{V}_{1}=-7 \mathrm{~V}$ |  |  | -0.8 |  |
| $\mathrm{I}_{\text {IH }} \quad$ High-level-enable input current | $\mathrm{V}_{\mathrm{IH}}=2.7 \mathrm{~V}$ |  |  |  | 20 | $\mu \mathrm{A}$ |
| IIL Low-level-enable input current | $\mathrm{V}_{\mathrm{IL}}=0.4 \mathrm{~V}$ |  |  |  | -100 | $\mu \mathrm{A}$ |
| $\mathrm{r}_{1} \quad$ Input resistance |  |  | 12 | 20 |  | k $\Omega$ |
| IOS Short-circuit output current | $\mathrm{V}_{\mathrm{ID}}=200 \mathrm{mV}$, | $\mathrm{V}_{\mathrm{O}}=0$ | -15 |  | -85 | mA |
| S | No load | Outputs enabled |  | 23 | 30 |  |
| ICC Supply current | No load | Outputs disabled |  | 19 | 26 | mA |

$\dagger$ All typical values are at $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.
$\ddagger$ The algebraic convention, in which the less positive (more negative) limit is designated minimum, is used in this data sheet for common-mode input voltage and threshold voltage levels only.
NOTE 5: This applies for power on and power off. Refer to TIA/EIA-485-A for exact conditions.
switching characteristics over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted)

SN65ALS176

|  | PARAMETER | TEST CONDITIONS |  | MIN | TYP† | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $t_{p d}$ | Propagation time | $\mathrm{V}_{\mathrm{ID}}=-1.5 \mathrm{~V} \text { to } 1.5 \mathrm{~V} \text {, }$ <br> See Figure 7 | $\mathrm{C}_{\mathrm{L}}=15 \mathrm{pF},$ |  |  | 25 | ns |
| $\mathrm{t}_{\mathrm{sk}}(\mathrm{p})$ | Pulse skew§ | $\mathrm{V}_{\mathrm{ID}}=-1.5 \mathrm{~V} \text { to } 1.5 \mathrm{~V} \text {, }$ <br> See Figure 7 | $\mathrm{C}_{\mathrm{L}}=15 \mathrm{pF}$, |  | 0 | 2 | ns |
| $\mathrm{t}_{\text {sk(lim) }}$ | Pulse skew ${ }^{\text {I }}$ | $\mathrm{R}_{\mathrm{L}}=54 \Omega,$ <br> See Figure 3 | $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$, |  |  | 15 | ns |
| tPZH | Output enable time to high level | $\mathrm{C}_{\mathrm{L}}=15 \mathrm{pF}$, | See Figure 8 |  | 11 | 18 | ns |
| tPZL | Output enable time to low level | $\mathrm{C}_{\mathrm{L}}=15 \mathrm{pF}$, | See Figure 8 |  | 11 | 18 | ns |
| tPHZ | Output disable time from high level | $\mathrm{C}_{\mathrm{L}}=15 \mathrm{pF}$, | See Figure 8 |  |  | 50 | ns |
| tplZ | Output disable time from low level | $\mathrm{C}_{\mathrm{L}}=15 \mathrm{pF}$, | See Figure 8 |  |  | 30 | ns |

$\dagger$ All typical values are at $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.
§ Pulse skew is defined as the |tpLH - tPHL| of each channel of the same device.
II Skew limit is the maximum difference in propagation delay times between any two channels of any two devices.
SN75ALS176, SN75ALS176A, SN75ALS176B

| PARAMETER |  |  | TEST CONDITIONS |  | MIN | TYP† | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $t_{\text {pd }}$ | Propagation time | 'ALS176 | $\mathrm{V}_{\mathrm{ID}}=-1.5 \mathrm{~V} \text { to } 1.5 \mathrm{~V} \text {, }$ <br> See Figure 7 | $C_{L}=15 \mathrm{pF}$, | 9 | 14 | 19 | ns |
|  |  | 'ALS176A |  |  | 10.5 | 14 | 18 |  |
|  |  | 'ALS176B |  |  | 11.5 | 13 | 16.5 |  |
| $\mathrm{tsk}_{\text {( }} \mathrm{p}$ ) | Pulse skew $\ddagger$ |  | $\mathrm{V}_{\mathrm{ID}}=-1.5 \mathrm{~V} \text { to } 1.5 \mathrm{~V} \text {, }$ <br> See Figure 7 | $\mathrm{C}_{\mathrm{L}}=15 \mathrm{pF}$, |  | 0 | 2 | ns |
| ${ }_{\text {tsk }}$ (lim) | Pulse skew§ | 'ALS176 | $\mathrm{R}_{\mathrm{L}}=54 \Omega,$ <br> See Figure 3 | $C_{L}=50 \mathrm{pF},$ |  |  | 10 | ns |
|  |  | 'ALS176A |  |  |  |  | 7.5 |  |
|  |  | 'ALS176B |  |  |  |  | 5 |  |
| tpZH | Output enable time to high level |  | $\mathrm{C}_{\mathrm{L}}=15 \mathrm{pF}$, | See Figure 8 |  | 7 | 14 | ns |
| tPZL | Output enable time to low level |  | $\mathrm{C}_{\mathrm{L}}=15 \mathrm{pF}$, | See Figure 8 |  | 20 | 35 | ns |
| tPHZ | Output disable time from high level |  | $\mathrm{C}_{\mathrm{L}}=15 \mathrm{pF}$, | See Figure 8 |  | 20 | 35 | ns |
| tplZ | Output disable time from low level |  | $\mathrm{C}_{\mathrm{L}}=15 \mathrm{pF}$, | See Figure 8 |  | 8 | 17 | ns |

$$
\dagger \text { All typical values are at } \mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C} \text {. }
$$

$\ddagger$ Pulse skew is defined as the $\mid \mathrm{tPLH}-\mathrm{tpHL}^{\prime}$ of each channel of the same device.
§ Skew limit is the maximum difference in propagation delay times between any two channels of any two devices.

PARAMETER MEASUREMENT INFORMATION


Figure 1. Driver $\mathrm{V}_{\mathrm{OD} 2}$ and $\mathrm{V}_{\mathrm{OC}}$

## PARAMETER MEASUREMENT INFORMATION



Figure 2. Driver $\mathrm{V}_{\mathrm{OD} 3}$


TEST CIRCUIT
NOTES: A. $\mathrm{C}_{\mathrm{L}}$ includes probe and jig capacitance.
B. The input pulse is supplied by a generator having the following characteristics: PRR $\leq 1 \mathrm{MHz}, 50 \%$ duty cycle, $\mathrm{t}_{\mathrm{r}} \leq 6 \mathrm{~ns}, \mathrm{t}_{\mathrm{f}} \leq 6 \mathrm{~ns}$, $Z_{O}=50 \Omega$.
C. $t_{d}(O D)=t_{d}(O D H)$ or $t_{d}(O D L)$

Figure 3. Driver Test Circuit and Voltage Waveforms



VOLTAGE WAVEFORMS

NOTES: A. $C_{L}$ includes probe and jig capacitance.
B. The input pulse is supplied by a generator having the following characteristics: $\mathrm{PRR} \leq 1 \mathrm{MHz}, 50 \%$ duty cycle, $\mathrm{t}_{\mathrm{r}} \leq 6 \mathrm{~ns}, \mathrm{t}_{\mathrm{f}} \leq 6 \mathrm{~ns}$, $Z_{O}=50 \Omega$.

Figure 4. Driver Test Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION


TEST CIRCUIT


VOLTAGE WAVEFORMS

NOTES: A. $C_{L}$ includes probe and jig capacitance.
B. The input pulse is supplied by a generator having the following characteristics: PRR $\leq 1 \mathrm{MHz}, 50 \%$ duty cycle, $\mathrm{t}_{\mathrm{r}} \leq 6 \mathrm{~ns}, \mathrm{t}_{\mathrm{f}} \leq 6 \mathrm{~ns}$, $Z_{O}=50 \Omega$.

Figure 5. Driver Test Circuit and Voltage Waveforms


Figure 6. Receiver $\mathrm{V}_{\mathrm{OH}}$ and $\mathrm{V}_{\mathrm{OL}}$ Test Circuit


NOTES: A. $C_{L}$ includes probe and jig capacitance.
B. The input pulse is supplied by a generator having the following characteristics: PRR $\leq 1 \mathrm{MHz}, 50 \%$ duty cycle, $\mathrm{t}_{\mathrm{r}} \leq 6 \mathrm{~ns}, \mathrm{t}_{\mathrm{f}} \leq 6 \mathrm{~ns}$, $Z_{O}=50 \Omega$.
C. $t_{p d}=t_{P L H}$ or $\mathrm{tPHL}^{2}$

Figure 7. Receiver Test Circuit and Voltage Waveforms

## PARAMETER MEASUREMENT INFORMATION



NOTES: A. $C_{L}$ includes probe and jig capacitance.
B. The input pulse is supplied by a generator having the following characteristics: PRR $\leq 1 \mathrm{MHz}, 50 \%$ duty cycle, $\mathrm{t}_{\mathrm{r}} \leq 6 \mathrm{~ns}, \mathrm{t}_{\mathrm{f}} \leq 6 \mathrm{~ns}$, $Z_{O}=50 \Omega$.

Figure 8. Receiver Test Circuit and Voltage Waveforms

TYPICAL CHARACTERISTICS $\dagger$


Figure 9

DRIVER
LOW-LEVEL OUTPUT VOLTAGE
vs
LOW-LEVEL OUTPUT CURRENT


Figure 10

DRIVER
DIFFERENTIAL OUTPUT VOLTAGE
vs
OUTPUT CURRENT


Figure 11

[^1]
## RECEIVER TYPICAL CHARACTERISTICS $\dagger$

RECEIVER
HIGH-LEVEL OUTPUT VOLTAGE
vs
HIGH-LEVEL OUTPUT CURRENT


Figure 12


Figure 14

RECEIVER
HIGH-LEVEL OUTPUT VOLTAGE
VS
FREE-AIR TEMPERATURE


Figure 13

RECEIVER LOW-LEVEL OUTPUT VOLTAGE VS
FREE-AIR TEMPERATURE


Figure 15

[^2]
## TYPICAL CHARACTERISTICS $\dagger$



Figure 16

RECEIVER OUTPUT VOLTAGE

VS
enable voltage


Figure 17
† Operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.
APPLICATION INFORMATION


NOTE A: The line should terminate at both ends in its characteristic impedance ( $\mathrm{R}_{\mathrm{T}}=\mathrm{Z}_{\mathrm{O}}$ ). Stub lengths off the main line should be kept as short as possible.

Figure 18. Typical Application Circuit

## PACKAGING INFORMATION

| Orderable Device | Status ${ }^{(1)}$ | Package Type | Package Drawing |  | Package Qty | Eco Plan ${ }^{(2)}$ | Lead/Ball Finish | MSL Peak Temp ${ }^{(3)}$ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SN65ALS176D | ACTIVE | SOIC | D | 8 | 75 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1 YEAR |
| SN65ALS176DR | ACTIVE | SOIC | D | 8 | 2500 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1 YEAR |
| SN65ALS176P | OBSOLETE | PDIP | P | 8 |  | None | Call TI | Call TI |
| SN75ALS176AD | ACTIVE | SOIC | D | 8 | 75 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1 YEAR |
| SN75ALS176ADR | ACTIVE | SOIC | D | 8 | 2500 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1 YEAR |
| SN75ALS176AP | ACTIVE | PDIP | P | 8 | 50 | Pb-Free (RoHS) | CU NIPDAU | Level-NC-NC-NC |
| SN75ALS176BD | ACTIVE | SOIC | D | 8 | 75 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1 YEAR |
| SN75ALS176BDR | ACTIVE | SOIC | D | 8 | 2500 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1 YEAR |
| SN75ALS176BP | ACTIVE | PDIP | P | 8 | 50 | Pb-Free (RoHS) | CU NIPDAU | Level-NC-NC-NC |
| SN75ALS176D | ACTIVE | SOIC | D | 8 | 75 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1 YEAR |
| SN75ALS176DR | ACTIVE | SOIC | D | 8 | 2500 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1 YEAR |
| SN75ALS176P | ACTIVE | PDIP | P | 8 | 50 | Pb-Free (RoHS) | CU NIPDAU | Level-NC-NC-NC |

${ }^{(1)}$ The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.
${ }^{(2)}$ Eco Plan - May not be currently available - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
None: Not yet available Lead (Pb-Free).
$\mathrm{Pb}-\mathrm{Free}$ (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed $0.1 \%$ by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Green (RoHS \& no $\mathbf{S b} / \mathbf{B r}$ ): TI defines "Green" to mean "Pb-Free" and in addition, uses package materials that do not contain halogens, including bromine ( Br ) or antimony $(\mathrm{Sb})$ above $0.1 \%$ of total product weight.
${ }^{(3)}$ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDECindustry standard classifications, and peak solder temperature.

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NOTES: A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. Falls within JEDEC MS-001

D (R-PDSO-G8)

## PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion not to exceed $0.006(0,15)$.
D. Falls within JEDEC MS-012 variation AA.

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[^0]:    $\dagger$ These devices meet or exceed the requirements of TIA/EIA-485-A, except for the Generator Contention Test (para. 3.4.2) and the Generator Current Limit (para. 3.4.3). The applied test voltage ranges are -6 V to 8 V for the SN75ALS176, SN75ALS176A, and SN75ALS176B and -4 V to 8 V for the SN65ALS180.

[^1]:    $\dagger$ Operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.

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